


<b>Search Notes</b>  	<b>Application/Control No.</b>  10824445	<b>Applicant(s)/Patent Under Reexamination</b>  LEE ET AL.
	<b>Examiner</b>  Tan, Alvin H	<b>Art Unit</b>  2173

SEARCHED			
Class	Subclass	Date	Examiner
715	708	5/22/07	/AT/
345	581	5/22/07	/AT/
Above	UPDATED	8/2/10	/AT/

SEARCH NOTES		
Search Notes	Date	Examiner
715/705, 712, 764, 810 (text search only - see search history printout)	5/23/07	/AT/
345/589, 617, 902 (text search only - see search history printout)	5/22/07	/AT/
348/177, 178 (text search only - see search history printout)	5/29/07	/AT/
EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, IBM_TDB) - See Search History Printout	5/25/07	/AT/
Above - UPDATED	8/2/10	/AT/
NPL (ACM Portal, Google.com)	5/25/07	/AT/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

--	--